In re Application of:

Berlin et al.

PATENT Atty Docket No.: INTEL1170(P15621)

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Amendments to the Claims

Claims 5-11, 16-19, 25-29, 34 and 36-37 are withdrawn.

Please amend claims 30-32 as indicated in the listing of claims.

The listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

What Is Claimed Is:

CLAIMS

1. (Original) A surface analysis device for identifying molecules by simultaneously scanning nanocodes on a surface of a substrate, comprising:

a scanning array capable of simultaneously scanning the nanocodes on the surface of the substrate; and

an analyzer coupled with the scanning array capable of receiving simultaneously scanned information from the scanning array and identifying molecules associated with the nanocodes.

- 2. (Original) The device of claim 1, wherein simultaneously scanning includes measuring the friction characteristics of the substrate and the nanocodes.
- 3. (Original) The device of claim 2, wherein the scanning array includes two or more atomic force microscopy (AFM) tips.
- 4. (Original) The device of claim 3, wherein the scanning array is a 3x3 array of AFM tips.
- 5. (Withdrawn) The device of claim 1, wherein simultaneously scanning includes measuring the electrical properties of the substrate and the nanocodes.

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- 6. (Withdrawn) The device of claim 5, wherein the scanning array includes two or more scanning tunneling microscopy (STM) tips.
- 7. (Withdrawn) The device of claim 6, wherein the scanning array is a 3x3 array of STM tips.
- 8. (Withdrawn) The device of claim 1, wherein simultaneously scanning includes: measuring the friction characteristics of the substrate and the nanocodes, and measuring the electrical properties of the substrate and the nanocodes.
- 9. (Withdrawn) The device of claim 8, wherein the scanning array includes a combination of atomic force microscopy (AFM) and scanning tunneling microscopy (STM) tips.
- 10. (Withdrawn) The device of claim 9, wherein the scanning array is a 3x3 array of tips.
- 11. (Withdrawn) The device of claim 1, wherein simultaneously scanning includes parallel scanning of the surface by the scanning array.
- 12. (Original) The device of claim 1, wherein the molecules include DNA molecules.
- 13. (Original) The device of claim 1, further comprising a substrate holder.
- 14. (Original) The device of claim 1, wherein the nanocodes include molecular assay labels.
- 15. (Original) A surface analysis device for identifying molecules by simultaneously scanning nanocodes on a surface of a substrate, comprising:

a substrate holder;

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a scanning array proximate the substrate holder capable of moving in relation to the substrate holder and simultaneously scanning nanocodes on the surface of the substrate; and an analyzer coupled with the scanning array capable of receiving simultaneously scanned information from the scanning array and identifying molecules associated with the nanocodes.

- 16. (Withdrawn) The device of claim 15, wherein simultaneously scanning includes measuring the friction characteristics of the substrate and the nanocodes.
- 17. (Withdrawn) The device of claim 15, wherein simultaneously scanning includes measuring with electrical characteristics of the substrate and the nanocodes.
- 18. (Withdrawn) The device of claim 15, wherein simultaneously scanning includes: measuring the friction characteristics of the substrate and the nanocodes, and measuring the electrical properties of the substrate and the nanocodes.
- 19. (Withdrawn) The device of claim 15, wherein simultaneously scanning includes parallel scanning of the substrate and nanocodes by the scanning array.
- 20. (Original) A method of identifying molecules by simultaneously scanning nanocodes on a surface of a substrate, comprising:

providing a substrate with nanocodes thereon; and simultaneously scanning the nanocodes using a surface analysis device having a scanning array.

21. (Original) The method of claim 20, further comprising: receiving the scanned information from the scanning array with an analyzer; and identifying the molecules associated with the nanocodes.

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- 22. (Original) The method of claim 20, wherein simultaneously scanning includes measuring the friction characteristics of the substrate and the nanocodes.
- 23. (Original) The method of claim 22, wherein the scanning array includes two or more atomic force microscopy (AFM) tips.
- 24. (Original) The method of claim 23, wherein the scanning array is a 3x3 array of AFM tips.
- 25. (Withdrawn) The method of claim 20, wherein simultaneously scanning includes measuring the electrical characteristics of the substrate and the nanocodes.
- 26. (Withdrawn) The method of claim 25, wherein the scanning array includes two or more scanning tunneling microscopy (STM) tips.
- 27. (Withdrawn) The method of claim 26, wherein the scanning array is a 3x3 array of STM tips.
- 28. (Withdrawn) The device of claim 20, wherein simultaneously scanning includes: measuring the friction characteristics of the substrate and the nanocodes, and measuring the electrical properties of the substrate and the nanocodes.
- 29. (Withdrawn) The device of claim 28, wherein the scanning array includes a combination of atomic force microscopy (AFM) and scanning tunneling microscopy (STM) tips.
- 30. (Currently amended) The method of claim 20, wherein the nanocodes <u>include one or more nanotube assemblies having are organic elements.</u>

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- 31. (Currently amended) The method of claim 20, wherein the nanocodes <u>include one or</u> more nanotube <u>assemblies having are</u> inorganic elements.
- 32. (Currently amended) The method of claim 20, wherein the nanocodes <u>include one or</u> more nanotube assemblies <u>having are</u> biochemical elements.
- 33. (Original) A method of accelerated scanning of nanocodes on a substrate to identify molecules associated with the nanocodes, comprising:

simultaneously scanning the nanocodes using a scanning array having two or more microscopy tips;

receiving the simultaneously scanned information from the scanning array with an analyzer; and

identifying the molecules associated with the nanocodes.

- 34. (Withdrawn) The method of claim 33, wherein the microscopy tips are scanning tunneling microscopy (STM) tips.
- 35. (Original) The method of claim 33, wherein the microscopy tips are atomic force microscopy (AFM) tips.
- 36. (Withdrawn) The method of claim 33, wherein the microscopy tips are a combination of atomic force microscopy (AFM) and scanning tunneling microscopy (STM) tips.
- 37. (Withdrawn) The method of claim 33, wherein simultaneously scanning includes parallel scanning by the scanning array.